



V. Janovec



298. Rozhovory

Application of linear scans in the analysis of epitaxial layers

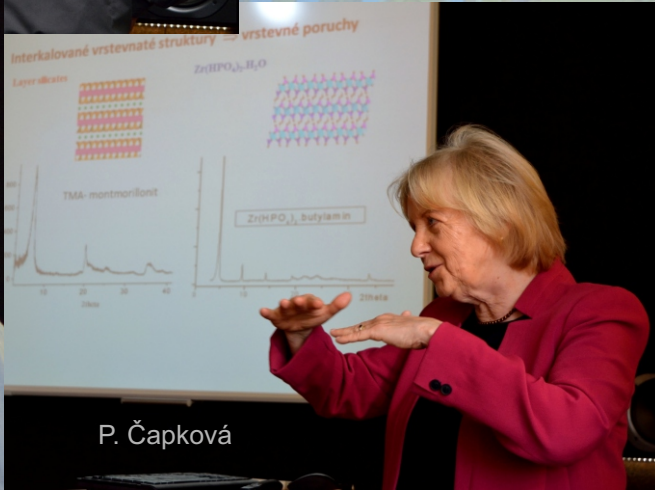
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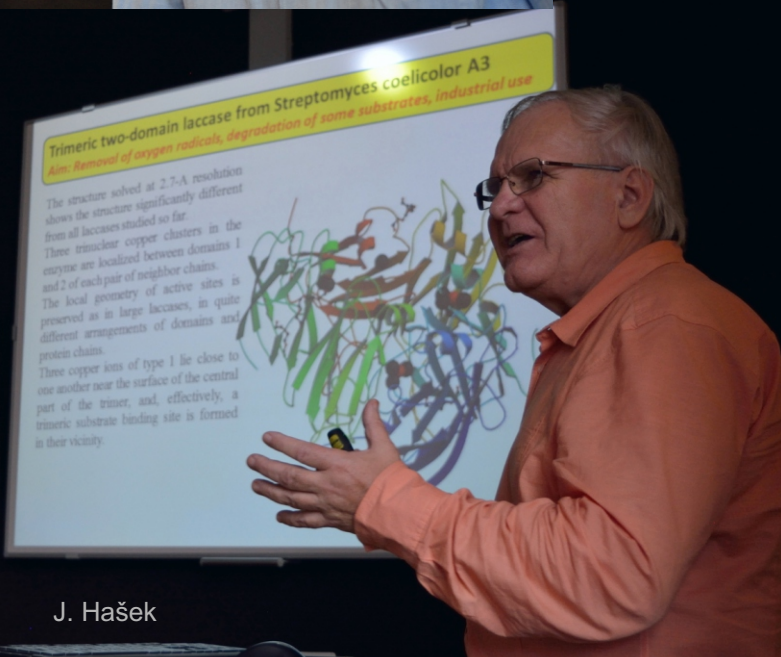
L. Čaplovič

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